

CYPRESS SEMICONDUCTOR CORPORATION PRODUCT RELIABILITY REPORT

QUARTER 4, 1997



PERFORM PER THE REQUIREMENT OF 25-00008, RELIABILITY MONITOR PROGRAM SPECIFICATION

Marc Hartranft
QA Engineering Department Manager

STANDARD STRESS TEST DESCRIPTIONS

<u>TEST</u>	<u>DESCRIPTION</u>
HTOL	High Temp Op Life, 150°C, 5.75V
HTOL2	High Temp Op Life, 125°C, 5.75V
HTSSL	High Temp Steady State Life, 150°C, 5.75V
HTSSL2	High Temp Steady State Life, 125°C, 5.75V
DRET	Data Retention Test, Data Bake 165°C, Plastic
DRET2	Data Retention Test, Data Bake 250°C, Hermetic
PCT	Pressure Cooker Test, 121°C, 100%RH, No Bias
HAST	Hi-Accel Saturation Test, 140°C, 85%RH, 5.5V Bias
TC	Temp Cycle, 125°C to -40°C
TC2	Temp Cycle, 150°C to -65°C
HTS	High Temp Storage, 165°C, No Bias
TEV	Temperature Extreme Verification

WAFER FAB AREAS

<u>FAB #</u>	<u>LOCATION</u>
CA	San Jose, California
TX	Round Rock, Texas
MN	Bloomington, Minnesota
FR	MHS, France

ASSEMBLY LOCATION

<u>ID</u>	<u>COMPANY/LOCATION</u>
KOREA-A	Anam-Buchon/Korea
ASAT-B	Asat/Hongkong
USA-C	Cypress/USA
PHIL-D	Dynesem/Philippines
USA-E	Cypress-Minnesota/USA
INDNS-F	Astra/Indonesia
TAIWAN-G	ASE/Taiwan
KOREA-H	Hyundai/Korea
MALAY-J	ASE/Malaysia
THLAND-K	TMS/Thailand
KOREA-L	Anam-Seoul/Korea
PHIL-M	Anam/Philippines
USA-N	Express/USA
INDNS-O	Omedata/Indonesia
USA-P	Pantronix/USA
KOREA-Q	Anam-Bupyong/Korea
PHIL-R	Cypress/Philippines
USA-S	ATM/USA
TAIWAN-T	OSE/Taiwan
MALAY-U	Unisem/Malaysia
USA-V	Aplus/USA
USA-W	Toshiba/USA
ALPHA-X	Cypress Bangkok/Thailand
ALPHA-Y	Alphatech/Thailand
THLAND-Z	Hana/Thailand

DESCRIPTION OF DATA TABLE COLUMN HEADINGS

<u>COLUMN HEADING</u>	<u>DESCRIPTION OF COLUMN CONTENTS</u>
Division	Cypress Manufacturing Division
Test	Common code for the stress performed. See table on previous page for detail.
Test Condition	Tem/humidity/bias condition for the stress. See table on previous for detail
Device ID	Cypress part number
Date Code	Week in which specific lot was marked/sealed/molded.
Lot Number	Manufacturing (assembly) lot number
Function	Generic product family at Cypress
Description	Brief description of device function
Technology	Fabrication process technology.
Process	Generic fabrication process
Pkg Material	Generic packaging material
Pkg Type	Common code for standard package configuration (PDIP=Plastic Dual-In-Line-Package).
Pkg Location	Country Location + Initial of assembly house (see table on prvious page for detail).
# Pins	Pin cont of package in which device is assembled.
Duration	Data Readpoint of stress. For Temp Cycle (TC) = Cycles; all other stresses=Hours.
# Test	Quantity of devices submitted to this stress/test.
# Failed	Quantity of devices failing at this specific readpoint.
Fail Mode	Failure analysis results from this test, if any.

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Division	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode		
CPD	DRET	165C/NO BIAS	CY7C611A-NC	M73055	9725	349703371	VME	RISC CONTRL	SRAM/LOGIC-L20	CMOS	TX	PQFP	HK-B	160	168 1000	77 77	0 0			
			CY7C63413-PC	97219	9731	519707719/	USB	USB	FAMOS-P26	CMOS	TX	PDIP	INDNS-O	40	168 552	76 76	0 0			
HAST	140C/3.63V	140C/5.5V	CY2278PAC	97386	9722	619703688	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	TSSO	KOREA-L	48	128 128	36 40	0 0	4 EOS		
			CY2276APVC	96513		3705598.A	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	128	50	0			
						619704633	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-A	56	128	45	0			
						3705598.A	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	128	50	0			
			CY2292SC	97181	9636	519610991	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	INDNS-O	16	128	45	0			
			CY7C63513-PVC	97219	9729	619705203/	USB	USB	FAMOS-P26	CMOS	TX	SSOP	CSPI-R	48	128	45	0			
HTOL	150C/3.65V	150C/3.65V	CY2273APVC	96513	9716	3705598	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-A	48	48 48 48 48 80 500	120 120 120 120 150 120 120	0 0 0 0 0 0 0			
						9724	619704148	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	TAIWAN-T	48	48 48 48 48 48 48 500	34 34 34 34 72 116 150 116	0 0 0 0 0 0 0		
						97223	9716	3705598	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-A	48	48 48 48 48 80 500	120 120 120 120 150 120	0 0 0 0 0 0	

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CPD	HTOL	150C/3.65V	CY2273APVC	97223	9724	619704148	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	TAIWAN-T	48	48	34	0	
														48	48	34	0	
														48	48	34	0	
														48	48	34	0	
														48	48	34	0	
														48	48	72	0	
														48	48	116	0	
														48	48	150	0	
														500	48	116	0	
																150C/5.50V	CY7C63101-SC	97223
		150C/5.75V	CY7C63413-PC	97219	9730	519707928/	USB	USB	FAMOS-P26	CMOS	TX	PDIP	INDNS-O	40	48	510	0	
48	48													510	0			
80	48													120	0			
	9731													519707719/	USB	USB	FAMOS-P26	CMOS
													48	48	614	0		
													80	48	116	0		
													500	48	116	0		
HTS	165C/NO BIAS	CY2276APVC	97385	9725	619702200	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	556	46	0		
													1000	1000	52	0		
													48	336	49	0		
													1000	1000	47	0		
													16	336	48	0		
													1000	1000	48	0		
HTSSL	150C/5.25V	CY7C63413-PC	97219	9730	519707928/	USB	USB	FAMOS-P26	CMOS	TX	PDIP	INDNS-O	40	80	76	0		
													168	168	76	0		
													40	80	76	0		
													168	168	76	0		
PCT	121C/100%RH	CY7C611A-NC	M73056	9725	349703371	VME	RISC CONTRL	SRAM/LOGIC-L20	CMOS	TX	PQFP	HK-B	160	96	77	5	5 LIFTING BOND/S	
													168	168	72	0	2 EXTERNAL CONTAMINATION	
			M74063	9728	349703682	VME	RISC CONTRL	SRAM/LOGIC-L20	CMOS	TX	PQFP	HK-B	160	96	76	0	39 EXTERNAL CONTAMINATION	
T/S	-55C TO 150C	CY2276APVC	97385	9725	619702200	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	100	51	0		

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CPD	T/S	-55C TO 150C	CY2276APVC	97385	9725	619702200	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	200	51	0	
			CY2278PAC	97386	9722	619703688	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	TSSO	KOREA-L	48	100 200	47 47	0 0	
			CY2292SC	97181	9636	519610991	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	INDNS-O	16	100 200	48 48	0 0	
TC		-40C TO 125C	CY7C611A-NC	M73054	9725	349703371	VME	RISC CONTRL	SRAM/LOGIC-L20	CMOS	TX	PQFP	HK-B	160	500 1500	48 48	0 0	
TC2		-65C TO 150C	CY2276APVC	96513		3705598.A	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	300 1000	50 50	0 0	
						3713782.03	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-A	56	300 1000	47 47	0 0	
						9714 3701143.03	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	300 1000	50 50	0 0	
			97385			3705598.A	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	300 1000	50 50	0 0	
						3713782.03	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-A	56	300 1000	47 47	0 0	
						9725 619702200	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SSOP	KOREA-L	56	300 1000	50 50	0 0	
			CY2278PAC	97386	9722	619703688	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	TSSO	KOREA-L	48	300 1000	47 47	0 0	
						619703689	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	TSSO	KOREA-L	48	300 1000	47 46	0 0	
						619703690	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	TSSO	KOREA-L	48	300 1000	45 45	0 0	
			CY2292SC	97181	9636	519610991	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	INDNS-O	16	300 1000	48 48	0 0	
						519610992	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	INDNS-O	16	300 1000	48 48	0 0	
						519610993	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	INDNS-O	16	300	48	0	

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Divi- sion	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Func- tion	Descr Description	Technology	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
CPD	TC2	-65C TO 150C	CY2292SC	97181	9636	519610993	TTECH	CLOCK SYN.	SRAM/LOGIC-L28	CMOS	MN	SOIC	INDNS-O	16	1000	48	0	
			CY7C63513-PVC	97219	9729	619705203/	USB	USB	FAMOS-P26	CMOS	TX	SSOP	CSPI-R	48	300 1000	46 46	0 0	
					9730	619705383	USB	USB	FAMOS-P26	CMOS	TX	SSOP	CSPI-R	48	300 1000	45 45	0 0	

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DCD	HAST	140C/5.5V	CY101E383-JC	97264	9625	349608970	CHNL	ECL/TTL	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	84	128	20	0				
															128	30	0				
			CY7B4663-JC	96392	9713	519703469	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PLCC	INDNS-O	28	128	50	0				
			CY7C136-JC	M74002	9716	349616269	SPCM	2K x 8 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	PHIL-M	52	128	78	0				
			CY7C4245-AC	M73084	9729	619704796	SPCM	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	64	128	38	0				
																128	40	0			
			CY7C4285-JC	97235	9736	219709635	SPCM	64Kx18 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	64	128	18	0				
														128	30	0					
			CY7C466A-JC	97222	9735	219709366	SPCM	64Kx9 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	32	128	36	0				
														128	58	0					
HTOL	150C/5.75V		CY7C0251-AC	97382	9732	619705578P	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	100	48	427	1	1	UNKNOWN		
							9736	619706519P	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	100	48	459	1	1	PARTICLE
								619706520P	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	100	48	472	0		
			CY7C145-JC	97414	9747	619709746	SPCM	8K x 9 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	KOREA-A	68	48	1010	0				
																80	120	0			
																500	120	0			
			CY7C4271-LMB	97242	9721	219705179/	SPCM	32Kx9 FIFO	SRAM/LOGIC-R30	CMOS	MN	LCC	ALPHA-X	32	48	324	0				
																48	333	4	4	PKG CHIP OUT	
																48	372	0			
																80	126	0	4	EOS	
																184	48	0			
													500	126	0						
			CY7C4285-JC	97235	9736	219709635	SPCM	64Kx18 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	64	80	394	0				
													500	394	0						
						9743	219711234	SPCM	64Kx18 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	64	80	383	0			
													500	383	0						
			CY7C466A-JC	97222	9735	219709366	SPCM	64Kx9 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	32	80	400	0				
													500	400	0						
						9739	219710431	SPCM	64Kx9 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	32	80	400	0			
													500	400	0						

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DCD	HTOL2	125C/5.75V	CY101E383-JC	97264	9625	349608970	CHNL	ECL/TTL	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	84	96	327	0		
															96	678	0		
				CY101E383-NC	97264	9716	619702398	CHNL	ECL/TTL	BICMOS-SM1	BiCMOS	TX	PQFP	HK-B	80	168	120	0	
															168	238	0		
															1000	119	0	5 THERMAL EOS	
															1000	236	0	2 EOS	
		125C/6.50		CY7B4663-JC	96392	9713	519703469	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PLCC	INDNS-O	28	80	118	0	
															500	118	0		
		125C/6.50V		CY7B4663-JC	96392	9713	519703469	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PLCC	INDNS-O	28	48	477	0	
															48	480	0		
														48	556	0			
HTSSL	150C/5.50V		CY7B4663-JC	96392	9713	519703469	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PLCC	INDNS-O	28	80	78	0		
															168	78	0		
				CY7C4285-JC	97235	9736	219709635	SPCM	64Kx18 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	64	80	162	0	
														168	162	0			
				CY7C466A-JC	97222	9735	219709366	SPCM	64Kx9 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	32	80	160	0	
		150C/5.75V		CY7C4271-LMB	97242	9721	219705179/	SPCM	32KX9 FIFO	SRAM/LOGIC-R30	CMOS	MN	LCC	ALPHA-X	32	80	78	0	
														168	78	0			
			CY7C4285-JC	97235	9743	219711234	SPCM	64Kx18 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	64	80	162	0		
														168	162	0			
			CY7C466A-JC	97222	9735	219709366	SPCM	64Kx9 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	32	168	160	0		
					9739	219710431	SPCM	64Kx9 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	32	80	160	0		
														168	160	0			
HTSSL2	125C/5.75V		CY101E383-JC	97264	9625	349608970	CHNL	ECL/TTL	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	84	168	80	0		
														336	78	0	1 EOS		
PCT	121C/100%RH		CY7B8392-JC	M74076	9716	519704354	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PLCC	INDNS-O	28	96	76	0		
															168	76	0		
						CY7C136-JC	M74003	9716	349616269	SPCM	2K x 8 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	PHIL-M	52	96	78
														168	78	0			
			CY7C4245-AC	M74059	9729	619705320	SPCM	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	64	96	77	0		

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DCD	PCT	121C/100%RH	CY7C4245-AC	M74059	9729	619705320	SPCM	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	64	168	77	0	
	TC2	-65 TO 150C	CY7C4271-LMB	97242	9721	219705179/	SPCM	32KX9 FIFO	SRAM/LOGIC-R30	CMOS	MN	LCC	ALPHA-X	32	100 1000	48 48	0 0	
		-65C TO 150C	CY101E383-JC	97264	9526	349512318	CHNL	ECL/TTL	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	84	300	48	0	
					9625	349608970	CHNL	ECL/TTL	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	84	300	50	0	
						349608976	CHNL	ECL/TTL	BICMOS-SM1	BiCMOS	TX	PLCC	KOREA-A	84	300	50	0	
			CY7B4663-JC	96392	9713	519703469	ENET	TRANSCEIVER	BICMOS-SM1	BiCMOS	TX	PLCC	INDNS-O	28	300	49	0	
			CY7B991-JC	M74071	9733	219708729	CHNL	PSCB	BICMOS-SM1	BiCMOS	TX	PLCC	ALPHA-X	32	300 500 1000	46 46 46	0 0 0	
			CY7C4245-AC	M74061	9729	619705320	SPCM	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	64	300 500 1000	46 46 46	0 0 0	
			CY7C4285-JC	97235	9736	219709635	SPCM	64Kx18 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	64	300 1000	90 90	0 0	
					9743	219711234	SPCM	64Kx18 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	64	300 1000	92 92	0 0	
			CY7C466A-JC	97222	9735	219709366	SPCM	64Kx9 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	32	300 1000	94 94	0 0	
					9739	219710431	SPCM	64Kx9 FIFO	SRAM/LOGIC-R32D	CMOS	MN	PLCC	ALPHA-X	32	300 1000	90 90	0 0	
	TEV	0 READ POINT	CY7B991-JC	M74065	9733	219708729	CHNL	PSCB	BICMOS-SM1	BiCMOS	TX	PLCC	ALPHA-X	32	-5 25 85	116 116 115	1 0 0	1 UNKNOWN

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MPD	DRET	165C/NO BIAS	CY27H256-PC	96404	9713	519703206/	PROM	32K x 8	FAMOS-P26	CMOS	TX	PDIP	INDNS-O	28	168 552	76 76	0 0		
	DRET2	250C/NO BIAS	CY27C010-WMB	97371	9735	219709517	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	PHIL-M	32	96 96 168 168	28 48 28 48	0 0 0 0		
			CY27H256-WC	96404	9712	219702752/	PROM	32K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	96 168	76 76	0 0		
HAST	140C/3.0V		CY7C1021V33-VC	97211	9727	619704310	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	128 256	64 64	0 0		
	140C/3.3V		CY7C1399-ZC	M73044	9645	349613772	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	CA	TSOP	PHIL-M	28	128 128	8 72	0 0	1 EOS	
	140C/3.63V		CY62128V-SC	97195	9732	619705603	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	128	47	0		
			CY62256V-VC	97412	9740	619708054	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	128 256	45 45	0 0		
						619708055	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	128 256	45 45	0 0		
						619708056	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	128 256	45 45	0 0		
						9745	619709132/	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	128 256	45 45	0 0	
						619709356/	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	128 256	47 47	0 0		
			CY62256V-ZI	M74057	9721	349702963	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	128	77	0		
			CY7C1399-VC	M74043	9727	619704667	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	MN	SOJ	PHIL-M	28	128	77	0		
	140C/3.6V		CY62128V-SC	97195	9732	619705603	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	256	47	0		
	140C/5.5V		CY27C010-JC	97371	9735	349704701	PROM	128K x 8	FAMOS-P26	CMOS	TX	PLCC	PHIL-M	32	128	47	0		
			CY27H256-JC	96404	9712	219702832	PROM	32K x 8	FAMOS-P26	CMOS	TX	PLCC	ALPHA-X	32	128	48	0		
			CY62128-SC	97195	9731	619705451	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	128	45	0		

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MPD	HAST	140C/5.5V	CY62128-SC	97195	9731	619705451	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	128 256	47 45	0 0			
			CY62256-SNC	M74008	9732	519707894	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	128	77	0			
			CY7C1009-VC	M74019	9732	619705971	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	CSPI-R	32	128	77	0			
			CY7C1021V33-VC	97211	9730	619705012	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	128	96	0			
			CY7C1049-VC	97344	9740	619707668	COMDTY	512K x 8	SRAM/LOGIC-R32D	CMOS	MN	SOJ	KOREA-L	36	128 256	50 50	0 0			
																		9741	619708016	COMDTY
			CY7C109-VC	97383	9731	519708179	COMDTY	128K x 8	SRAM/LOGIC-R32D	CMOS	MN	SOJ	INDNS-O	32	128	49	0			
																		97411	9731	519708180
						M74025	9734	519708340	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	128	77	0	
			CY7C109-ZC	97348	9726	619703878	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	32	128	48	0			
																		97351	9735	349704960
			CY7C1399-ZI	M72053	9704	349700156	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	CA	TSOP	PHIL-M	28	128	65	0			
			CY7C1599-VC	97202	9727	619704763/	COMDTY	32K x 8(5)	SRAM/LOGIC-R32D	CMOS	MN	SOJ	CSPI-R	28	128 256	47 47	0 0			
			CY7C185-VI	M74030	9734	519708252	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	SOJ	INDNS-O	28	128	77	0			
			CY7C186-ZC	M72029	9713	619701453	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	TSOP	KOREA-Q	32	128 128	22 56	0 0			
																		M73019	9723	619703886
				M74013	9725	619704309	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	TSOP	KOREA-Q	32	128	76	0			
			CY7C199-VC	97476		619708288	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	128 128	45 48	0 0			
																		9736	619707330/	COMDTY

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MPD	HAST	140C/5.5V	CY7C199-VC	97476	9740	619707989	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	128	45	0					
																	128	50	0			
								9744	619708989	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	128	47	0		
				M72006	9715	619702274/	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M			28	128	79	34	34	TOP SIDE DEFECT	
				M73003	9720	219704818	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X			28	128	23	1	1	EOS/1	TOP SIDE DEFECT
																	128	52	0			
				M73006	9724	619703780	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M			28	128	77	2	2	TOP SIDE DEFECT	
M74049	9729	619705121	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	SOJ	CSPI-R			28	128	21	0							
														128	56	0						
			CY7C199-ZI	M74036	9730	619705361	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	CSPI-R	28	128	77	0					
HTOL	150C/3.80V		CY62128V-SC	97195	9732	619705603	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	48	407	0					
															80	121	0					
															80	121	0					
															500	12	0					
															500	121	0					
															500	395	0					
				CY7C1021V33-VC	97211	9727	619704310	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	80	538	0				
															500	538	1	1	UNKNOWN			
															1000	527	0					
															2000	526	0	1	EOS			
					9730	619705012	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	80	528	0					
															500	528	1	1	UNKNOWN			
					9733	619705819	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	80	525	0					
														500	525	0						
	150C/5.75V		CY27C010-JC	97371	9735	349704701	PROM	128K x 8	FAMOS-P26	CMOS	TX	PLCC	PHIL-M	32	48	531	0	5	EOS			
							9738	519705071	PROM	128K x 8	FAMOS-P26	CMOS	TX	PLCC	PHIL-M	32	48	510	0			
			CY27C010-WMB	97371	9735	219709517	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	PHIL-M	32	184	47	0					
			CY27H256-PC	96404	9713	519703206	PROM	32K x 8	FAMOS-P26	CMOS	TX	PDIP	INDNS-O	28	80	116	0					
						519703206/	PROM	32K x 8	FAMOS-P26	CMOS	TX	PDIP	INDNS-O	28	48	500	0					

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MPD	HTOL	150C/5.75V	CY27H256-WC	96404	9712	219702752/	PROM	32K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	48	500	0													
															80	116	0													
															500	116	0													
			CY62128-SC	97195	9731	619705451	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	48	25	0													
															48	510	0													
															80	121	0													
															500	121	0													
															500	198	0													
															1000	121	0													
			2000	121	0																									
			CY62256-SNC	97397	9735	349704738	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	48	498	0													
															9735	519709206/	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	48	3589	1	5	EOS/1	UNKNOWN
															519709289/	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	48	3600	0				
			CY7C1009-VC	97411	9736	619706411	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	TAIWAN-G	32	80	522	0													
															500	522	0	1	EOS											
															97229	9724	219705887	COMDTY	512K x 8	SRAM/LOGIC-R32D	CMOS	MN	CSOJ	ALPHA-X	32	184	45	0		
			CY7C1048-FJMB	97315	9724	219705887	COMDTY	512K x 8	SRAM/LOGIC-R32D	CMOS	MN	CSOJ	ALPHA-X	32	80	116	2	1	CRACKED DIE/1	BROKEN BO										
															80	291	0	5	EOS											
															184	45	0													
															500	114	0													
500	291	0													4	EOS														
CY7C1599-VC	97202	9727	619704763/	COMDTY	32K x 8(5)	SRAM/LOGIC-R32D	CMOS	MN	SOJ	CSPI-R	28	80	125	0																
												500	124	0	1	EOS														
												1000	114	0																
CY7C199-VC	97476	9736	619707330/	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	48	535	0																
												80	535	0																
												500	533	0	2	EOS														
												1000	120	0																
												9740	619707989	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	48	535	0						
												80	527	0																
500	527	0																												
9742	519711442D	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	INDNS-O	28	48	540	0																		
										80	540	0																		
										500	534	0	5	EOS																

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MPD	HTOL2	125C/3.80V	CY7C1399-ZI	M72052	9704	349700156	SYNC	32K x 8	SRAM/LOGIC-R30	CMOS	CA	TSOP	PHIL-M	28	96	113	0	
															500	113	0	
															1000	113	0	
															2000	113	0	
		125C/5.75V	CY27C010-PC	M72009	9707	349700791	PROM	128K x 8	FAMOS-P26	CMOS	TX	PDIP	KOREA-H	32	96	118	0	
															500	118	0	
															1000	118	0	
															2000	100	0	18 EOS
			CY27H010-WC	M73069	9727	219706861/	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	96	120	0	
															500	120	0	
															1000	120	0	
															2000	120	0	
			CY62256-SNC	M72080	9721	519705680	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	96	120	0	
															500	120	0	
															1000	120	0	
															2000	119	0	
				M73038	9720	519705368	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	96	120	0	
															500	120	0	
															1000	119	0	
															2000	119	0	
		CY7C1009-VC	M72086	9647	349613727	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	96	123	0		
														500	123	1	1 SPEED DEGRADATION	
														1000	122	0		
														2000	122	0		
		CY7C109-VC	M73034	9722	519705873	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	96	120	0		
														500	120	0		
														1000	120	0		
														2000	119	0	1 EOS	
		CY7C185-45PC	M72068	9717	219703823	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	96	120	0		
														500	120	0		
														1000	120	0		
														2000	120	0		
			M73028	9723	219705968	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	96	119	0		
														500	119	0		
														1000	119	0		
														2000	119	0		

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MPD	HTOL2	125C/5.75V	CY7C199-VC	M73032	9724	619703780	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	96	120	0		
															500	120	0		
															1000	120	0		
															2000	120	0		
			CY7C199-ZC	M73076	9721	349703035	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	TSOP	PHIL-M	28	96	117	0		
															500	117	0		
														1000	117	0			
														2000	116	0			
HTS	165C/NO BIAS		CY62128-SC	97195	9731	619705451	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	336	45	0		
															1000	45	0		
			CY7C1021V33-VC	97211	9727	619704310	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	336	48	0		
																1000	48	0	
			CY7C109-VC	97383	9731	519708179	COMDTY	128K x 8	SRAM/LOGIC-R32D	CMOS	MN	SOJ	INDNS-O	32	336	49	0		
																500	48	0	
																1000	48	0	
CY7C109-ZC	97348	9726	619703878	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	32	336	48	0					
													1000	48	0				
CY7C1599-VC	97202	9727	619704763/	COMDTY	32K x 8(5)	SRAM/LOGIC-R32D	CMOS	MN	SOJ	CSPI-R	28	336	48	0					
													1000	48	0				
CY7C199-VC	97476	9736	619707330/	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	336	48	0					
													500	48	0				
													1000	48	0				
HTSSL	150C/3.63V		CY7C1021V33-VC	97211	9727	619704310	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	80	160	0		
															168	160	0		
						9730	619705012	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	80	160	0	
															168	160	0		
						9733	619705819	COMDTY	64K x16	SRAM/LOGIC-R42	CMOS	MN	SOJ	TAIWN-G	44	80	156	0	
														168	156	0			
150C/3.80			CY62128V-SC	97195	9732	619705603	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	80	78	0		
														168	78	0			
150C/3.90V			CY62256V-VC	97412	9740	619708054	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	80	76	0		
														168	76	0			

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MPD	HTSSL	150C/3.90V	CY62256V-VC	97412	9740	619708055	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	80 168	76 76	0 0															
						619708056	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	80 168	76 76	0 0															
						9745 619709132/	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	80 168	76 76	0 0															
						619709356/	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	80 168	77 77	0 1 0	EOS														
	150C/5.50V	CY7C109-VC	97411	9731	519708180	COMDTY	128K x 8	SRAM/LOGIC-R32D	CMOS	MN	SOJ	INDNS-O	32	80 168	79 78	0 0	0 0															
																			97476	9736	619707330/	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	80 168	81 81	0 0
	150C/5.75V	CY27H256-PC	96404	9713	519703206/	PROM	32K x 8	FAMOS-P26	CMOS	TX	PDIP	INDNS-O	28	80 168	78 78	0 0	0 0															
																			CY27H256-WC	96404	9712	219702752/	PROM	32K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	80 168	77 77
		CY62128-SC	97195	9731	619705451	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	80 168	78 78	0 0																
																	CY7C1048-FJMB	97315	9724	219705887	COMDTY	512K x 8	SRAM/LOGIC-R32D	CMOS	MN	CSOJ	ALPHA-X	32	80 168	78 75	0 0	
	CY7C1599-VC	97202	9727	619704763/	COMDTY	32K x 8(5)	SRAM/LOGIC-R32D	CMOS	MN	SOJ	CSPI-R	28	80 168	80 79	0 0	1 1																EOS
																	HTSSL2	125C/5.50V	CY62256-SNC	M72081	9721	519705680	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	96	
	500	118	0																													
1000	118	0																														
2000	118	0																														
M73039	9720	519705368	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	96	120	0	500	120	0																
														1000	120	0																
														1000	120	0																
														2000	120	0																

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MPD	HTSSL2	125C/5.50V	CY7C1009-VC	M72087	9647	349613727	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	96	123	0		
															500	123	0		
																1000	123	0	
																2000	123	0	
		125C/5.75V		CY27C010-PC	M72010	9707	349700791	PROM	128K x 8	FAMOS-P26	CMOS	TX	PDIP	KOREA-H	32	96	119	0	
															500	119	0		
				CY27H010-WC	M73070	9727	219706861/	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	96	120	0	
															500	120	0		
															1000	120	0		
															2000	120	0		
				CY7C185-45PC	M72069	9717	219703823	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	96	120	0	
															500	120	0		
														1000	120	0			
														2000	120	0			
			CY7C199-VC	M73033	9724	619703780	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	96	120	0		
														500	120	1	1	TOPSIDE CRACKS	
														1000	119	0			
														2000	118	1	1	EOS/1 LIFTING BOND	
			CY7C199-ZC	M73077	9721	349703035	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	TSOP	PHIL-M	28	96	117	0		
														500	117	0			
														1000	117	0			
														2000	117	0			
	LTOL	-30C/6.5V	CY7C199-VC	97476	9736	619707330/	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	500	45	0		
PCT	121C/100%RH		CY62256-SNC	M74007	9732	519707894	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	96	77	0		
															168	77	0		
			CY62256V-ZI	M74058	9721	349702963	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	96	78	0		
																168	77	0	
			CY7C1009-VC	M74017	9732	619705971	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	CSPI-R	32	96	77	0		
													168	77	0				
			CY7C109-VC	M74023	9734	519708340	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	96	77	6	6	TOPSIDE CRACKS
														168	69	0			
			CY7C1399-VC	M74041	9727	619704667	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	MN	SOJ	PHIL-M	28	96	77	0		

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MPD	PCT	121C/100%RH	CY7C1399-VC	M74041	9727	619704667	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	MN	SOJ	PHIL-M	28	168	77	0		
			CY7C1399-ZI	M72055	9704	349700156	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	CA	TSOP	PHIL-M	28	96	59	18	18	OTHERS
			CY7C185-VI	M74031	9734	519708252	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	SOJ	INDNS-O	28	96 168	77 77	0 0		
			CY7C186-ZC	M74011	9725	619704309	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	TSOP	KOREA-Q	32	96 168	45 45	0 0		
			CY7C199-VC	M74047	9729	619705121	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	SOJ	CSPI-R	28	96 168	77 77	0 0		
T/S		-55C TO 150C	CY7C109-ZC	97348	9726	619703878	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	32	100 200	48 48	0 0		
TC2	-65 TO 150C		CY27C010-WMB	97371	9735	219709517	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	PHIL-M	32	100 1000	48 48	0 0		
			CY27H256-WC	96404	9712	219702752/	PROM	32K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	28	100 1000	46 46	0 0		
			CY7C1048-FJMB	97229	9724	219705887	COMDTY	512K x 8	SRAM/LOGIC-R32D	CMOS	MN	CSOJ	ALPHA-X	32	100 1000	45 45	0 0		
				97315	9724	219705887	COMDTY	512K x 8	SRAM/LOGIC-R32D	CMOS	MN	CSOJ	ALPHA-X	32	100 1000	45 45	0 0		
			CY27C010-JC	97371	9735	349704701	PROM	128K x 8	FAMOS-P26	CMOS	TX	PLCC	PHIL-M	32	300 1000	47 47	0 0		
	-65C TO 150C			CY27H256-JC	96404	9712	219702832	PROM	32K x 8	FAMOS-P26	CMOS	TX	PLCC	ALPHA-X	32	300 1000	48 48	0 0	
				CY62128-SC	97195	9731	619705451	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	300	45	0	
				CY62128V-SC	97195	9732	619705603	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWAN-G	32	300 300 1000	46 47 47	0 0 0	1 EOS
				CY62256-SNC	M74009	9732	519707894	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	300 500 1000	46 43 43	0 0 0	

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MPD	TC2	-65C TO 150C	CY62256V-VC	97412	9740	619708054	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	300 1000	90 90	0 0					
						619708055	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	300 1000	90 90	0 0					
						619708056	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	300 1000	90 90	0 0					
						9745	619709132/	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	300	90	0				
							619709356/	COMDTY	32K x 8	SRAM/LOGIC-R42	CMOS	MN	SOJ	CSPI-R	28	300 1000	90 90	0 0				

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MPD	TC2	-65C TO 150C	CY7C1049-VC	97344	9741	619708016	COMDTY	512K x 8	SRAM/LOGIC-R32D	CMOS	MN	SOJ	KOREA-L	36	300 1000	49 49	0 0	
			CY7C107-VC	97383	9732	519708413	COMDTY	1M x 1	SRAM/LOGIC-R32D	CMOS	MN	SOJ	INDNS-O	32	300 1000	48 48	0 0	
						519708434	COMDTY	256K x 4	SRAM/LOGIC-R32D	CMOS	MN	SOJ	INDNS-O	32	300 1000	48 48	0 0	
			CY7C109-20VC	M73030	9716	619701975	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	KOREA-L	32	300	84	0	
			CY7C109-VC	97383	9731	519708179	COMDTY	128K x 8	SRAM/LOGIC-R32D	CMOS	MN	SOJ	INDNS-O	32	300 1000	49 49	0 0	
				97411	9731	519708180	COMDTY	128K x 8	SRAM/LOGIC-R32D	CMOS	MN	SOJ	INDNS-O	32	300 1000	48 48	0 0	
				M73010	9722	519705873	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	300	48	2	2 TOPSIDE CRACKS
				M73043	9725	519706781	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	300 1000	50 42	8	8 TOPSIDE CRACKS
				M74024	9734	519708340	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	300	46	11	11 TOPSIDE CRACKS
			CY7C109-ZC	97348	9726	619703876	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	32	300 1000	48 48	0 0	
						619703877	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	32	300 1000	48 48	0 0	
						619703878	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	32	300 1000	48 48	0 0	
				97351	9735	349704960	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-GQ	32	300 1000	48 48	0 0	
						349704961	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-GQ	32	300 1000	48 47	0 0	
						349704962	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-GQ	32	300 1000	48 48	0 0	
			CY7C1399-VC	M74042	9727	619704667	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	MN	SOJ	PHIL-M	28	300 500 1000	46 46 46	0 0 0	
			CY7C1399-ZC	M73045	9645	349613772	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	CA	TSOP	PHIL-M	28	300	50	0	

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MPD	TC2	-65C TO 150C	CY7C1399-ZC	M73045	9645	349613772	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	CA	TSOP	PHIL-M	28	1000	50	0				
			CY7C1399-ZI	M72054	9704	349700156	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	CA	TSOP	PHIL-M	28	300	48	0				
			CY7C1599-VC	97202	9727	619704763/	COMDTY	32K x 8(5)	SRAM/LOGIC-R32D	CMOS	MN	SOJ	CSPI-R	28	300 1000	48 48	0 0				
			CY7C185-45PC	M72071	9717	219703823	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	300 1000	48 48	0 0				
			CY7C185-VI	M74029	9734	519708252	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	SOJ	INDNS-O	28	300 500 1000	46 46 46	0 0 0				
			CY7C186-ZC	M74012	9725	619704309	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	TSOP	KOREA-Q	32	300 500 1000	76 76 76	0 0 0				
			CY7C199-VC	97476	9736	619707330/	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	300 1000	48 48	0 0				
							9740	619707989	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	300 1000	50 50	0 0		
							M74048	9729	619705121	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	SOJ	CSPI-R	28	300 500 1000	46 46 46	0 0 0	
							M73079	9721	349703035	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	TSOP	PHIL-M	28	300 1000	46 45	0 0	
							M74037	9730	619705361	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	CSPI-R	28	300	40	0	
			TEV	0 READ POINT		CY62256-SNC	M74004	9732	519707894	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	-5 25 85	116 116 116	0 0 0	
						CY7C109-VC	M74020	9734	519708340	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	-5 25 85	116 116 115	0 0 0	1 1 UNKNOWN
CY7C1399-VC	M80108	9744				619709194	SYNC	32K x 8	SRAM/LOGIC-R31	CMOS	MN	SOJ	PHIL-M	28	-5 25 85	117 117 117	0 0 0				
CY7C185-VI	M74026	9734				519708252	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	SOJ	INDNS-O	28	-5	116	0				

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MPD	TEV	0 READ POINT	CY7C185-VI	M74026	9734	519708252	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	SOJ	INDNS-O	28	25 85	116 116	0 0		
			CY7C199-VC	M80112	9746	619709733	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	TX	SOJ	CSPI-R	28	-5 25 85	117 117 117	0 0 0		
			CY7C199-ZI	M74032	9730	619705361	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	CSPI-R	28	-5 25 85	116 116 116	0 0 0		

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PLD	HAST	140C/5.5V	CY7C341-JI	M72057	9711	619700872	MAX	REPROG.PAL	FAMOS-P20	CMOS	TX	PLCC	KOREA-A	84	128	12	0	
															128	18	0	
															128	18	0	
															128	32	1	1 TOP SIDE DEFECT
	HTOL	150C/5.75V	CY7C341-HMB	97314	9735	219709372	MAX	REPROG.PAL	FAMOS-P20	CMOS	TX	CERQ	ALPHA-X	84	48	235	0	
						219709373	MAX	REPROG.PAL	FAMOS-P20	CMOS	TX	CERQ	ALPHA-X	84	48	171	0	
			CY7C341-RMB	97314	9735	219709278	MAX	REPROG.PAL	FAMOS-P20	CMOS	TX	WPGA	ALPHA-X	84	48	183	0	
			CY7C374I-YMB	97341	9729	219707592	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	CLCC	ALPHA-X	84	184	48	0	
			CY7C375I-UMB	97061	9649	349701384	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	CQFP	USA-GA	160	184	50	0	
			PALCE22V10-DMB	97492	9747	219711972	PLD	FLASH ERAS.	FLASH-FL24D	CMOS	TX	CERD	ALPHA-X	24	24	1103	0	
															72	1100	0	
						219711973	PLD	FLASH ERAS.	FLASH-FL24D	CMOS	TX	CERD	ALPHA-X	24	24	735	0	
															56	735	0	
						219711974	PLD	FLASH ERAS.	FLASH-FL24D	CMOS	TX	CERD	ALPHA-X	24	24	1061	0	
															56	1061	0	
	TC2	-65 TO 150C	CY7C375I-UMB	97061	9649	349701384	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	CQFP	USA-GA	160	100	48	0	
															1000	48	0	
		-65C TO 150C	CY7C374I-JC	M73058	9704	219700578	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	PLCC	ALPHA-X	84	300	47	1	1 TOPSIDE CRACKS
	TEV	0 READ POINT	CY7C341-JI	M74079	9735	219709449	MAX	REPROG.PAL	FAMOS-P20	CMOS	TX	PLCC	ALPHA-X	84	-5	109	0	
															25	109	0	7 ESD
															85	109	0	